## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10061982	KUTARAGI ET AL.
Examiner	Art Unit
Cloud, Joiya M	2144

SEARCHED						
Class	Subclass	Date	Examiner			
709	229, 217	01/05/2007	JC			
473	29	01/05/2007	JC			
725	6	01/05/2007	JC			

SEARCH NOTES					
Search Notes	Date	Examiner			
EAST, US Patent, USPGPUB, DERWENT, JPO, EPO, IBM DB	01/05/2007	JC			
101 CONSULTATION SPE W. VAUGHN	01/05/2007	JC			
NPL GOOGLE SEARCH, IEEE XPlore	01/05/2007	JC			
EIC FAST AND FOCUS SEARCH- search specialist Alyson Dill	01/05/2007	JC			
consulted William Vaughn-RCE	05/21/2007	JC			
EIC FAST AND FOCUS SEARCH-search specialist Byron Mimms	10/24/2007	JC			
UPDATED SEARCH	10/27/2007	JC			
UPDATED SEARCH	05/28/2008	JC			

INTERFERENCE SEARCH					
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709	229,217	10/27/2007	JC		
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